WS-575-C-RT

Halogen-Free Ball-Attach Flux

Introduction

Indium Corporation's **Ball-Attach Flux WS-575-C-RT** allows customers to use a completely halogen-free (NIA = no intentionally added halogens) single-step ball-attach process to eliminate the costly, wasteful, and warpage-inducing effects of prefluxing. The "Standard Ball-Attach Process" diagram shows the typical two-step flux processing that is needed to create reliable, ball-to-pad joints from final BGA balling. The prefluxing step can only be eliminated if the flux has sufficient activity to overcome the extent of the oxidation on copper, and create strong solder joints. **WS-575-C-RT** is customer-proven to be able to eliminate the need for multiple fluxing steps before final ball-attach.



Features

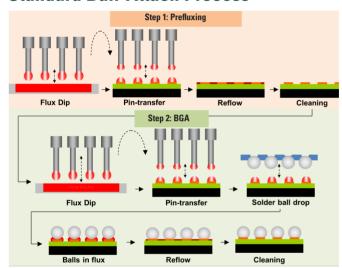
• Halogen-free – no intentionally added (NIA) halogens

- NIA means that the flux is formulated to be free of halogens
- Eliminates process costs and warpage due to "prefluxing"
 - No extra fluxing, reflow, cleaning, and substrate warpage (see right)
- Reflows in air or nitrogen
 - Can eliminate the cost of nitrogen
- No "missing ball"
 - Tack during heating and fast soldering ensure balls stay in place during reflow
- Excellent solderability on a wide range of surfaces
 - Good results on AuNi and even on oxidized Cu-OSP (up to 0.3mm thick OSP)
- Uniform pin transfer over extended periods
 - Avoids changes of joint quality over time and uneven deposit sizes, which can lead to "missing ball"
- Low-voiding
 - Increases joint strength

• Designed for Pb-free applications

- Suitable for all high-tin solders: SAC105, SAC305, SAC38, SAC405
- Cleanable with room temperature DI water only
 - Saves money on water heating
- No "white residue"
 - Cleaning the flux residues at lower temperatures avoids the formation of white residues
- Stable at room temperature
 - Ease of storage and use without crystals or gel balls
 - Ready to use, straight from the jar or cartridge

Standard Ball-Attach Process



Flux Properties

Property	Value	Test Method	
Flux Type Classification	ORH0	J-STD-004 (IPC-TM-650: 2.3.32 and 2.3.33)	
Typical Viscosity	20kcps (5mins)	Brookfield HB DVII +-CP (5rpm)	
SIR (Ohms, after cleaning)	Pass (>10 ⁸ after 7 days @ 85°C & 85% RH)	J-STD-004 (IPC-TM-650: 2.6.33 IPC-B-24)	
Typical Acid Number	95mg KOH/g	Titration	
Typical Tack Strength	360g	J-STD-005 (IPC- TM-650:2.4.44)	
Shelf Life	0-30°C for 6 months	Viscosity Change/ Microscope Examination	

All information is for reference only. Not to be used as incoming product specifications.



Ball-Attach Flux WS-575-C-RT

Pin Transfer

Viscosity Test Method

- Equipment
- Brookfield Cone and Plate
- Model: DV3THBCB
- Parameters
 - Spindle: CP-51
 - Temperature: 25°C
 - RPMs: 20RPM



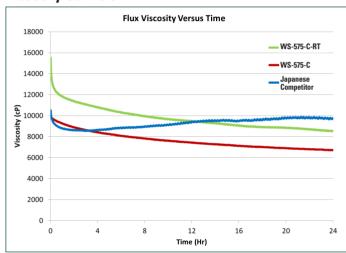
Tack Test Method

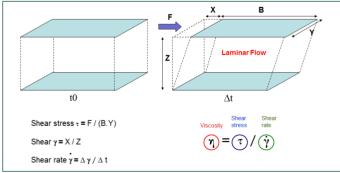
- Equipment
- Texture Technologies TA.XT2
- Parameters
 - Ambient Conditions
 - Humidity: 50% ± 3%
 - Room Temperature:21.5°C ± 2°C

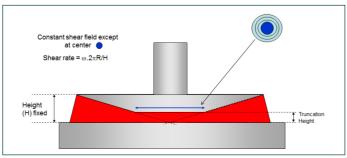


Comparative Viscosities as a Function of Time

Viscosity Controls

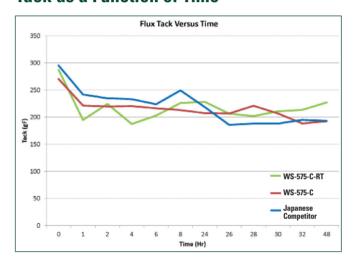






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Tack as a Function of Time



Consistent Flux Deposition

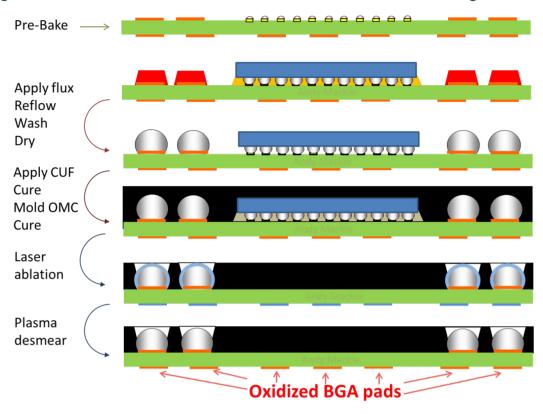
WS-575-C-RT's consistent viscosity and tack ensure consistent flux deposit sizes and eliminate missing ball before reflow.



Ball-Attach Flux WS-575-C-RT

Reflow

OSP Degradation From FCBGA Substrate Treatment Before BGA Balling



Test Materials and Reflow

- Solder Spheres
 - SAC305, 28mil
 - 7-hour bake @ 130°C
- Reflow
 - Soak (preheat) reflow profile
 - Air reflow
- Substrates
 - OSP substrates

Eliminate Extra Costs and Warpage

For flip-chip BGA, bottom pads can become extremely oxidized. **WS-575-C-RT** eliminates the need for a prefluxing step, which reduces:

- Process cost
- Package warpage
- UPH

Simulated Preconditioning

- None
- Bake
 - 2-hour bake @ 170°C
 - -7-hour bake @ 130°C
- Bake and Cleaner
 - 2-hour bake @ 170°C
 - Cleaned with aggressive aqueous flux cleaner @ 96°C
 - 7-hour bake @ 130°C

• Double Bake and Cleaner

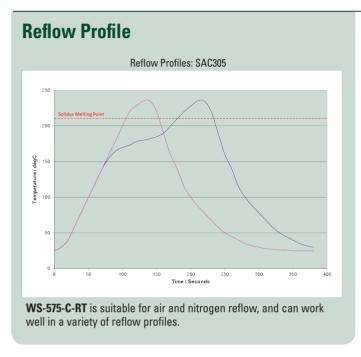
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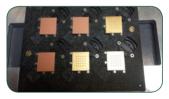
Ball-Attach Flux WS-575-C-RT

Reflow



Movement During Reflow (MDR) and Solderability Test Method

- · Print flux onto metallized surface
- · Place spheres onto flux deposit
- Reflow (air or N, [typical])
- · Measure reflowed height deposit
- · Calculate percent spread (wetting)
- · Calculate mean sphere center movement (MDR)





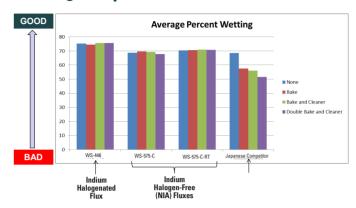
Copper OSP Substrates



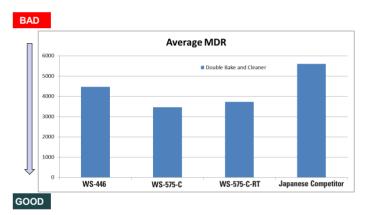




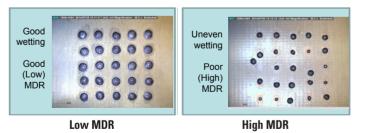
Wetting Comparison



MDR for Different Fluxes



MDR Correlates with Missing Ball



Eliminate Missing Ball and Increase Joint Strength

WS-575-C-RT's eliminates missing ball during reflow by high viscosity and rapid soldering.

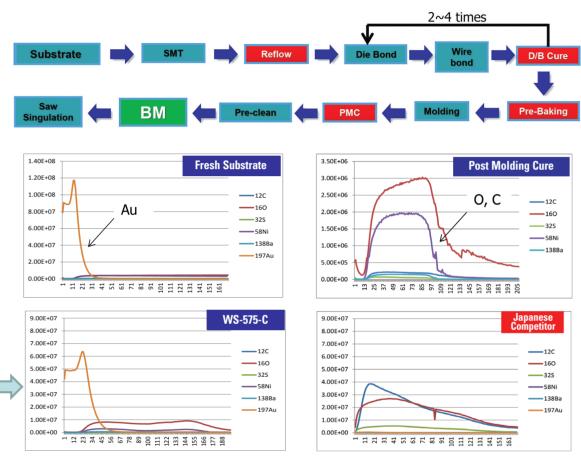
Joint strength is high due to good wetting.

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Cleaning

Secondary Ion Mass Spectrometry (SIMS) Shows Species at the Surface



Cleaning Test

- Very mild (forcing) condition
 - Deionized water temperature: 36°C
 - Deionized water conductivity $\leq 1.00 \mu S/cm$
 - Zero pressure
 - Flow rate 5cc/minute
 - Time of cleaning: 1 minute



	WS-446	WS-575-C	WS-575-C-RT	Japanese Competitor
Baked and Cleaner OSP	0 0	0 0	0 0	0 0
	WS-446	WS-575-C	WS-575-C-RT	Japanese Competitor
Double				
Baked	0 0	0 0	0 0	0 0
and Cleaner	6 6	6 0	0.0	0 0
OSP	0			

Simplified, Low-Cost Cleaning

WS-575-C-RT is cleanable with room temperature deionized (DI) water only, eliminating chemical cleaning costs and costs of heating water.



Ball-Attach Flux WS-575-C-RT

Final Test

Customer and Process Validation







Flux on Flux Tray
Flux is normal on flux tray

Ball Mount

After ball mount, flux and ball position are good



Post Reflow

No missing ball and flux residue is clear



Post DI W Clean

No missing ball and no flux residue

Recommended Semiconductor Fluxes and Solder Pastes

Material Group	Material Type	Material Name	Flux Type	Halogen-Free	Application	Comments
	Wafer Bumping Flux Flip-Chip Flux	WS-3543	Water wash	No Intentionally Added (NIA)	Spin coating	High viscosity for taller copper pillars and larger bumps (>40 microns)
		WS-3401	Water wash	NIA	Spin coating	Low viscosity for smaller pillars and bumps
		WS-446	Water wash	No	Dipping	Best flux for poor solderability
FLUX		WS-688	Water wash	NIA	Dipping (can be strayed at 60°C)	Minimizes voiding
		WS-580	Water wash	NIA	Dipping	Best all-around HF flip-chip flux Easily cleaned
		WS-3555	Water wash	NIA	Spraying	Ultra-low residue no-clean
		NC-26A	No-clean	NIA	Dipping	Best compatibility with CUF/MUF
		NC-26S	No-clean	NIA	Dipping	Avoids capillary flow up to die surface for fine-pitch devices
	Ball-Attach Flux	WS-3600	Water wash	No	Pin transfer	Best flux for poor solderability
		WS-575-C-RT	Water wash	NIA	Pin transfer	Best ball-attach flux for missing ball Eliminates the prefluxing step for OSP

Material Group	Material Type	Material Name	Flux Type	Halogen-Free	Alloy	Comments
SOLDER PASTE	Die-Attach	SMQ®75	No-clean ("Power- Safe")	NIA	All high-Pb and Sb-containing alloys	Ultra-low residue "Power-Safe" (no-clean) paste suitable for clip-bonded devices
		SMQ®51-SC	Solvent clean	No		Best all-around cleanable die-attach paste
		BiAgX [®]	Solvent clean	NIA	BiAgX® - mixed alloy system	High-temperature Pb-free solder paste
	SiP Solder Paste	Indium3.2HFA	Water wash	Halogen Compliant	SAC305 and other Pb-free	Type 6-SG solder paste suitable for ultrafine pitch printing Designed for 01005 and smaller discrete devices

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